

Notice of References Cited

Application/Control No.

10/551,671

Applicant(s)/Patent Under
Reexamination
ADAMEK ET AL.

Examiner

SHEELA C. CHAWAN

Art Unit

2624

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,224,357 B2	05-2007	Chen et al.	345/420
*	B	US-7,003,161 B2	02-2006	Tessadro, Ana M.	382/199
*	C	US-5,255,354	10-1993	Mahoney, James V.	382/203
*	D	US-6,343,150 B1	01-2002	Darrell et al.	382/218
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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